

# **Die Datasheet**

# GA50JT17-CAL

1700 V

20 mΩ

100 A

85

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# Normally – OFF Silicon Carbide Junction Transistor

### Features

- 210 °C Maximum Operating Temperature
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low Output Capacitance
- Positive Temperature Coefficient of RDS.ON
- Suitable for Connecting an Anti-parallel Diode

### **Advantages**

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 µs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal Distortion
- High Amplifier Bandwidth





Die Size = 4.35 mm x 4.35 mm

### Applications

• Down Hole Oil Drilling, Geothermal Instrumentation

 $V_{\text{DS}}$ 

 $\mathbf{h}_{\text{FE}}$ 

R<sub>DS(ON)</sub>

I<sub>D</sub> @ 25 °C

- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

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### Section I: Absolute Maximum Ratings

### (T<sub>c</sub> = 25 °C unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit	Notes
Drain – Source Voltage	V <sub>DS</sub>	$V_{GS} = 0 V$	1700	V	
Continuous Drain Current	Ι <sub>D</sub>	$T_{\rm C} = 25^{\circ}{\rm C}$	100	А	
Continuous Drain Current	ID	$T_C > 125$ °C, assumes $R_{thJC} < 0.26$ °C/W	50	А	
Continuous Gate Current	l <sub>G</sub>		3.5	А	
Turn-Off Safe Operating Area	RBSOA	T <sub>VJ</sub> = 210 °C, Clamped Inductive Load	$I_{D,max} = 50$ @ $V_{DS} \le V_{DSmax}$	А	Fig. 16
Short Circuit Safe Operating Area	SCSOA	$T_{VJ} = 210 \ ^{\circ}C$ , $I_G = 1 \ A$ , $V_{DS} = 1200 \ V$ , Non Repetitive	>20	μs	
Reverse Gate – Source Voltage	V <sub>SG</sub>		30	V	
Reverse Drain – Source Voltage	V <sub>SD</sub>		25	V	
Operating Junction and Storage Temperature	$T_{j},T_{stg}$		-55 to 210	°C	
Maximum Processing Temperature	T <sub>Proc</sub>	10 min. maximum	325	°C	

### **Section II: Static Electrical Characteristics**

Denemerten	Currente e l	Symphol Conditions		Value			
Parameter	Symbol	Conditions	Min.	Typical	Max.	Unit	Notes
A: On State							
Drain – Source On Resistance	R <sub>DS(ON)</sub>	$ \begin{array}{l} I_{D} = 50 \mbox{ A}, \mbox{ T}_{j} = 25 \mbox{ °C} \\ I_{D} = 50 \mbox{ A}, \mbox{ T}_{j} = 150 \mbox{ °C} \\ I_{D} = 50 \mbox{ A}, \mbox{ T}_{j} = 175 \mbox{ °C} \end{array} $		20 36 42		mΩ	Fig. 4
Gate – Source Saturation Voltage	$V_{\text{GS},\text{SAT}}$	$I_D = 50 \text{ A}, I_D/I_G = 40, T_j = 25 \text{ °C}$ $I_D = 50 \text{ A}, I_D/I_G = 30, T_j = 175 \text{ °C}$		3.42 3.23		V	Fig. 7
DC Current Gain	h <sub>FE</sub>	$ \begin{array}{l} V_{DS} = 8 \ V, \ I_D = 50 \ A, \ T_j = 25 \ ^\circ C \\ V_{DS} = 8 \ V, \ I_D = 50 \ A, \ T_j = 125 \ ^\circ C \\ V_{DS} = 8 \ V, \ I_D = 50 \ A, \ T_j = 175 \ ^\circ C \end{array} $		80 60 50		_	Fig. 5
B: Off State							
Drain Leakage Current	I <sub>DSS</sub>	$ \begin{array}{l} V_{DS} = 1700 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 25 \; ^{\circ} C \\ V_{DS} = 1700 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 150 \; ^{\circ} C \\ V_{DS} = 1700 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 175 \; ^{\circ} C \end{array} $		10 10 20		μA	Fig. 8
Gate Leakage Current	I <sub>SG</sub>	V <sub>SG</sub> = 20 V, T <sub>j</sub> = 25 °C		20		nA	

### **Section III: Dynamic Electrical Characteristics**

Parameter	Symbol	Conditions		Value		Unit	Notes
Farameter Syllic		Conditions		lin. Typical Max.		Unit	Notes
A: Capacitance and Gate Charg	e						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 1200 V, <i>f</i> = 1 MHz		7205		pF	Fig. 9
Reverse Transfer/Output Capacitance	C <sub>rss</sub> /C <sub>oss</sub>	V <sub>DS</sub> = 1200 V, <i>f</i> = 1 MHz		120		pF	Fig. 9
Output Capacitance Stored Energy	Eoss	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 1200 V, <i>f</i> = 1 MHz		100		μJ	Fig. 10
Effective Output Capacitance, time related	$C_{\text{oss,tr}}$	$I_{D} = constant, V_{GS} = 0 \text{ V}, V_{DS} = 01200 \text{ V}$		194		pF	
Effective Output Capacitance, energy related	$C_{\text{oss,er}}$	$V_{GS} = 0 \text{ V}, V_{DS} = 01200 \text{ V}$		139		pF	
Gate-Source Charge	Q <sub>GS</sub>	V <sub>GS</sub> = -53 V		55		nC	
Gate-Drain Charge	$Q_{GD}$	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 01200 V		233		nC	
Gate Charge - Total	$Q_{G}$			288		nC	
B: Switching <sup>1</sup>	Paula area	<i>f</i> = 1 MHz, V <sub>AC</sub> = 50 mV, V <sub>DS</sub> = 0 V,		0.59		Ω	
	$V_{GS} = 0 V, T_i = 175 V_{GS}$						
Internal Gate Resistance – ON	R <sub>G(INT-ON)</sub>	$V_{GS} > 2.5 \text{ V}, V_{DS} = 0 \text{ V}, T_j = 175 ^{\circ}\text{C}$		0.09		Ω	
Turn On Delay Time	t <sub>d(on)</sub>	$T_j = 25 \text{ °C}, V_{DS} = 1200 \text{ V},$		17		ns	
Fall Time, V <sub>DS</sub>	t <sub>f</sub>	$I_{\rm D} = 50$ A, Inductive Load		47		ns	Fig. 11, 13
Turn Off Delay Time	t <sub>d(off)</sub>	Refer to Section V for additional driving information.		39		ns	
Rise Time, V <sub>DS</sub>	tr	unving information.		25		ns	Fig. 12, 14
Turn On Delay Time	t <sub>d(on)</sub>			17		ns	
Fall Time, V <sub>DS</sub>	t <sub>f</sub>	$T_j = 175 ^{\circ}\text{C},  V_{\text{DS}} = 1200  \text{V},$		47		ns	Fig. 11
Turn Off Delay Time	t <sub>d(off)</sub>	$I_D = 50 \text{ A}$ , Inductive Load		44		ns	
Rise Time, V <sub>DS</sub>	t <sub>r</sub>			23		ns	Fig. 12
Turn-On Energy Per Pulse	Eon	T <sub>j</sub> = 25 °C, V <sub>DS</sub> = 1200 V,		1830		μJ	Fig. 11, 13
Turn-Off Energy Per Pulse	E <sub>off</sub>	$I_D = 50 \text{ A}$ , Inductive Load		628		μJ	Fig. 12, 14
Total Switching Energy	E <sub>tot</sub>	Refer to Section V.		2458		μJ	
Turn-On Energy Per Pulse	Eon	T 175 % 1200 \/		1800		μJ	Fig. 11
Turn-Off Energy Per Pulse	E <sub>off</sub>	$T_{j} = 175 ^{\circ}C, V_{DS} = 1200 V,$ $-I_{D} = 50 A, Inductive Load -$		577		μJ	Fig. 12
Total Switching Energy	otal Switching Energy E <sub>tot</sub>			2377		μJ	

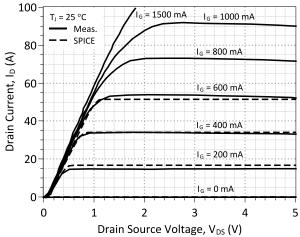
 $^{\rm 1}$  – All times are relative to the Drain-Source Voltage  $V_{\rm DS}$ 



# GA50JT17-CAL

### **Section IV: Figures**

### **A: Static Characteristics**





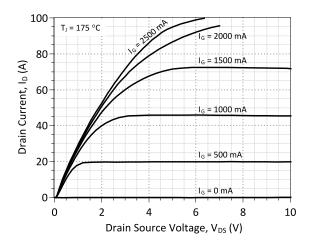


Figure 3: Typical Output Characteristics at 175 °C

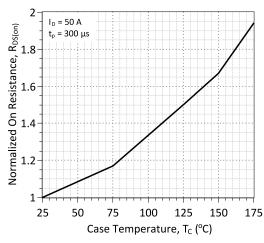


Figure 5: Normalized On-Resistance vs. Temperature

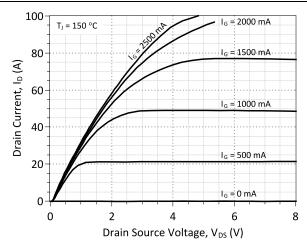


Figure 2: Typical Output Characteristics at 150 °C

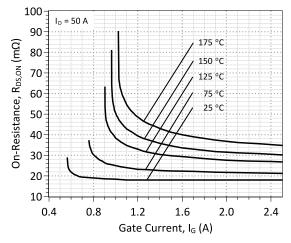
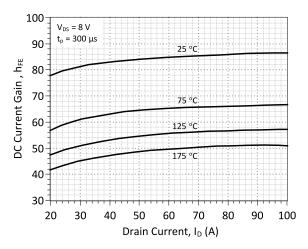


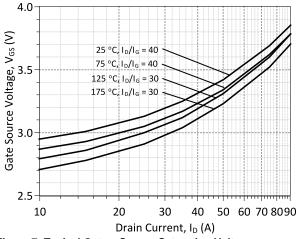
Figure 4: On-Resistance vs. Gate Current





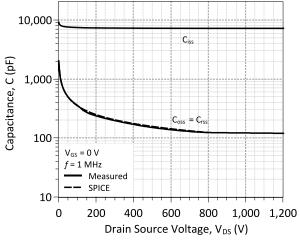
# **Die Datasheet**

# GA50JT17-CAL

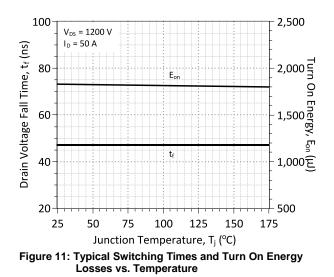












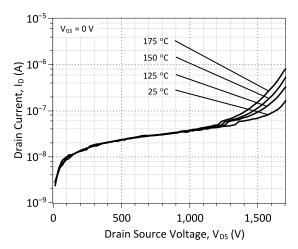


Figure 8: Typical Blocking Characteristics

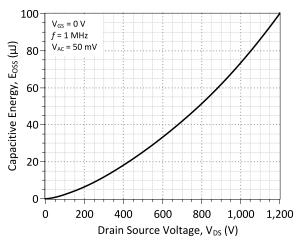
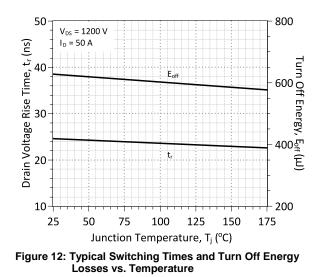


Figure 10: Energy Stored in Output Capacitance



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# **Die Datasheet**

# GA50JT17-CAL

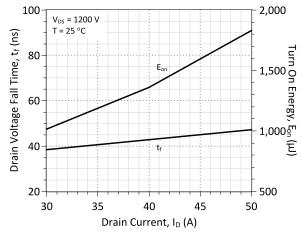


Figure 13: Typical Switching Times and Turn On Energy Losses vs. Drain Current

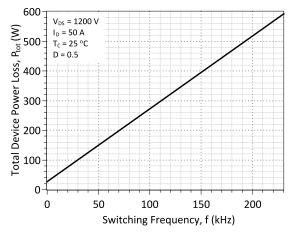


Figure 15: Typical Hard Switched Device Power Loss vs. Switching Frequency<sup>2</sup>

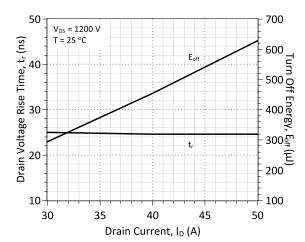


Figure 14: Typical Switching Times and Turn Off Energy Losses vs. Drain Current

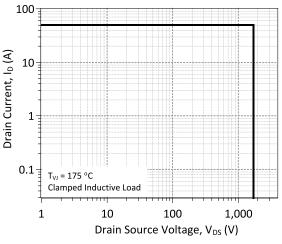


Figure 16: Turn-Off Safe Operating Area

<sup>2</sup> - Representative values based on device conduction and switching loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.



### Section V: Driving the GA50JT17-CAL

Drive Topology	Gate Drive Power Consumption	Switching Frequency	Application Emphasis	Availability
TTL Logic	High	Low	Wide Temperature Range	Coming Soon
Constant Current	Medium	Medium	Wide Temperature Range	Coming Soon
High Speed – Boost Capacitor	Medium	High	Fast Switching	Production
High Speed – Boost Inductor	Low	High	Ultra Fast Switching	Coming Soon
Proportional	Lowest	High	Wide Drain Current Range	Coming Soon
Pulsed Power	Medium	N/A	Pulse Power	Coming Soon

### A: Static TTL Logic Driving

The GA50JT17-CAL may be driven using direct (5 V) TTL logic after current amplification. The (amplified) current level of the supply must meet or exceed the steady state gate current ( $I_{G,steady}$ ) required to operate the GA50JT17-CAL. The power level of the supply can be estimated from the target duty cycle of the particular application.  $I_{G,steady}$  is dependent on the anticipated drain current ID through the SJT and the DC current gain  $h_{FE}$ , it may be calculated from the following equation. An accurate value of the  $h_{FE}$  may be read from Figure 6.

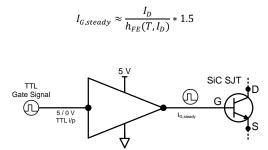


Figure 17: TTL Gate Drive Schematic

### **B: High Speed Driving**

The SJT is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 18 which features a positive current peak during turn-on, a negative current peak during turn-off, and continuous gate current to remain on.

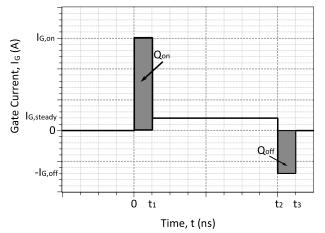


Figure 18: An idealized gate current waveform for fast switching of an SJT.

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge,  $Q_G$ , for turn-on is supplied by a burst of high gate current,  $I_{G,on}$ , until the gate-source capacitance,  $C_{GS}$ , and gate-drain capacitance,  $C_{GD}$ , are fully charged.

$$Q_{on} = I_{G,on} * t_1$$
$$Q_{on} \ge Q_{gs} + Q_{gd}$$

Ideally,  $I_{G,pon}$  should terminate when the drain voltage falls to its on-state value in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the  $I_{G,on}$  pulse is affected by the parasitic inductances,  $L_{par}$  in the device package and drive circuit. A voltage developed across the parasitic inductance in the source path,  $L_s$ , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The voltage applied to the gate pin should be maintained high enough, above the  $V_{GS,sat}$  (see Figure 7) level to counter these effects.

A high negative peak current,  $-I_{G,off}$  is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with  $V_{GS} = 0$  V, a negative gate voltage  $V_{GS}$  may be used in order to speed up the turn-off transition.

Two high-speed drive topologies for the SiC SJTs are presented below.

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#### B:1: High Speed, Low Loss Drive with Boost Capacitor, GA15IDDJT22-FR4

The GA50JT17-CAL may be driven using a High Speed, Low Loss Drive with Boost Capacitor topology in which multiple voltage levels, a gate resistor, and a gate capacitor are used to provide fast switching current peaks at turn-on and turn-off and a continuous gate current while in on-state. An evaluation gate drive board (GA15IDDJT22-FR4) utilizing this topology is commercially available for low-side driving, its datasheet provides additional details.

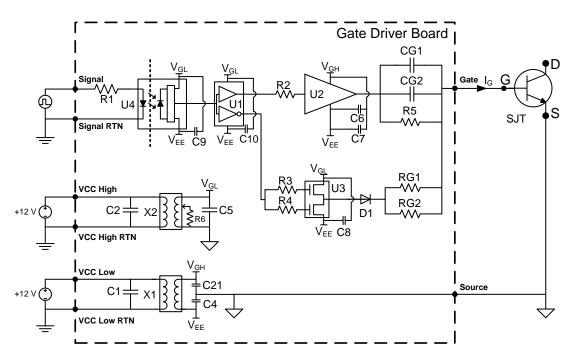


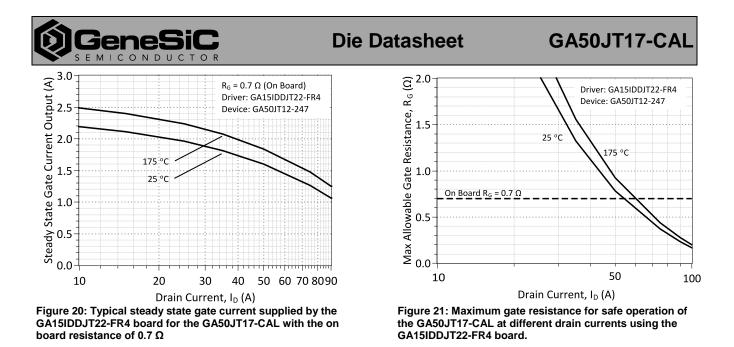
Figure 19: Topology of the GA03IDDJT30-FR4 Two Voltage Source gate driver.

The GA15IDDJT22-FR4 evaluation board comes equipped with two on board gate drive resistors (RG1, RG2) pre-installed for an effective gate resistance<sup>3</sup> of  $R_G = 0.7 \Omega$ . It may be necessary for the user to reduce RG1 and RG2 under high drain current conditions for safe operation of the GA50JT17-CAL. The steady state current supplied to the gate pin of the GA50JT17-CAL with on-board  $R_G = 0.7 \Omega$ , is shown in **Error! Reference source not found.** The maximum allowable safe value of  $R_G$  for the user's required drain current can be read from **Error! Reference source not found.** 

#### For the GA50JT17-CAL, $R_G$ must be reduced for $I_D \ge -60$ A for safe operation with the GA15IDDJT22-FR4.

For operation at  $I_D \ge \sim 60$  A,  $R_G$  may be calculated from the following equation, which contains the DC current gain  $h_{FE}$  (Figure 6) and the gate-source saturation voltage  $V_{GS,sat}$  (Error! Reference source not found.).

$$R_{G,max} = \frac{\left(4.7V - V_{GS,sat}\right) * h_{FE}(T, I_D)}{I_D * 1.5} - 0.1\Omega$$



#### B:2: High Speed, Low Loss Drive with Boost Inductor

A High Speed, Low-Loss Driver with Boost Inductor is also capable of driving the GA50JT17-CAL at high-speed. It utilizes a gate drive inductor instead of a capacitor to provide the high-current gate current pulses  $I_{G,on}$  and  $I_{G,off}$ . During operation, inductor L is charged to a specified  $I_{G,on}$  current value then made to discharge  $I_L$  into the SJT gate pin using logic control of S<sub>1</sub>, S<sub>2</sub>, S<sub>3</sub>, and S<sub>4</sub>, as shown in Figure 22. After turn on, while the device remains on the necessary steady state gate current  $I_{G,steady}$  is supplied from source  $V_{CC}$  through R<sub>G</sub>. Please refer to the article "A current-source concept for fast and efficient driving of silicon carbide transistors" by Dr. Jacek Rąbkowski for additional information on this driving topology.<sup>4</sup>

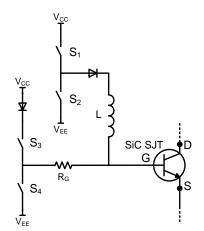


Figure 22: Simplified Inductive Pulsed Drive Topology

 $^{3}$  - R<sub>G</sub> = (1/RG1 + 1/RG2)<sup>-1</sup>. Driver is pre-installed with RG1 = RG2 = 7.5  $\Omega$ 

<sup>4</sup> – Archives of Electrical Engineering. Volume 62, Issue 2, Pages 333–343, ISSN (Print) 0004-0746, DOI: 10.2478/aee-2013-0026, June 2013



#### **C: Proportional Gate Current Driving**

For applications in which the GA50JT17-CAL will operate over a wide range of drain current conditions, it may be beneficial to drive the device using a proportional gate drive topology to optimize gate drive power consumption. A proportional gate drive relies on instantaneous drain current  $I_D$  feedback to vary the steady state gate current  $I_{G,steady}$  supplied to the GA50JT17-CAL.

#### **C:1: Voltage Controlled Proportional Driver**

The voltage controlled proportional driver relies on a gate drive IC to detect the GA50JT17-CAL drain-source voltage  $V_{DS}$  during on-state to sense I<sub>D</sub>. The gate drive IC will then increase or decrease I<sub>G,steady</sub> in response to I<sub>D</sub>. This allows I<sub>G,steady</sub>, and thus the gate drive power consumption, to be reduced while I<sub>D</sub> is relatively low or for I<sub>G,steady</sub> to increase when is I<sub>D</sub> higher. A high voltage diode connected between the drain and sense protects the IC from high-voltage when the driver and GA50JT17-CAL are in off-state. A simplified version of this topology is shown in Figure 23, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/

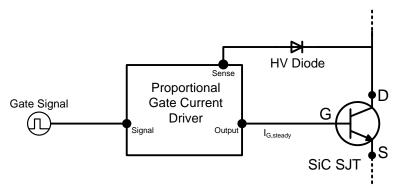


Figure 23: Simplified Voltage Controlled Proportional Driver

#### **C:2: Current Controlled Proportional Driver**

The current controlled proportional driver relies on a low-loss transformer in the drain or source path to provide feedback  $I_D$  of the GA50JT17-CAL during on-state to supply  $I_{G,steady}$  into the device gate.  $I_{G,steady}$  will then increase or decrease in response to  $I_D$  at a fixed forced current gain which is set be the turns ratio of the transformer,  $h_{force} = I_D / I_G = N_2 / N_1$ . GA50JT17-CAL is initially tuned-on using a gate current pulse supplied into an RC drive circuit to allow  $I_D$  current to begin flowing. This topology allows  $I_{G,steady}$ , and thus the gate drive power consumption, to be reduced while  $I_D$  is relatively low or for  $I_{G,steady}$  to increase when is  $I_D$  higher. A simplified version of this topology is shown in Figure 24, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/.

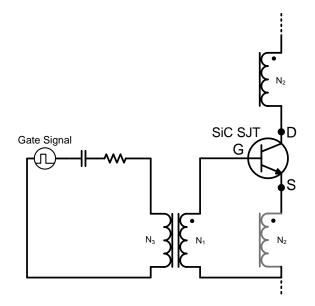
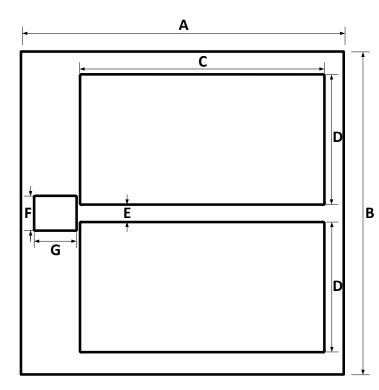


Figure 24: Simplified Current Controlled Proportional Driver

### **Section VI: Mechanical Parameters**

Die Dimensions	4.35 x 4.35	mm <sup>2</sup>	171 x 171	mil <sup>2</sup>		
Die Area total / active	18.92/16.56	mm <sup>2</sup>	29330/25677	mil <sup>2</sup>		
Die Thickness	360	μm	14	mil		
Wafer Size	100	mm	3937	mil		
Flat Position	0	deg	0	deg		
Die Frontside Passivation		Polyimide				
Gate/Source Pad Metallization		4000 nm Al				
Bottom Drain Pad Metallization		400 nm Ni + 200 nm Au				
Die Attach	Elect	Electrically conductive glue or solder				
Wire Bond		AI ≤ 12 mil (Source) AI ≤ 5 mil (Gate)				
Reject ink dot size		Φ ≥ 0.3 mm				
	Store in	Store in original container, in dry nitrogen,				
Recommended storage environment	< 6 month	< 6 months at an ambient temperature of 23 °C				

### **Section VII: Chip Dimensions**



		mm	mil
DIE	А	4.35	171
DIE	В	4.35	171
	С	3.30	130
SOURCE WIREBONDABLE	D	1.75	69
	E	0.24	9
GATE WIREBONDABLE	F	0.46	18
	G	0.57	22



Revision History						
Date Revision Comments Supersedes						
2016/02/26	2	Updated Electrical Characteristics				
2015/02/06	1	Updated Electrical Characteristics				
2014/07/14	0	Initial release				

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**Die Datasheet** 

### Section VIII: SPICE Model Parameters

GeneSiC

SEMICONDUCTOR

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit\_sic/baredie/sjt/GA50JT17-CAL\_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA50JT17-CAL.

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 OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
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* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
 Models accurate up to 2 times rated drain current.
.model GA50JT17 NPN
+ IS
           9.833E-48
+ ISE
           1.073E-26
+ EG
           3.23
+ BF
           89
+ BR
           0.55
           9000
+ IKF
+ NF
           1
+ NE
           2
+ RB
           0.95
+ IRB
           0.005
+ RBM
           0.073
+ RE
           0.004
+ RC
           0.0125
+ CJC
           2.124E-9
+ VJC
           3.788
+ MJC
           0.537
           6.026E-09
+ CJE
           3.1791
+ VJE
           0.5295
+ MJE
+ XTI
           3
           -1.5
+ XTB
           9.00E-3
+ TRC1
+ VCEO
           1700
+ ICRATING 50
+ MFG
           GeneSiC Semiconductor
* End of GA50JT17 SPICE Model
```